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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

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Application Serial No	10/678,513
Filing Date	October 3, 2003
Inventor	
Assignee	Micron Technology, Inc.
Group Art Unit	
Examiner	Brook Kebede
Attorney's Docket No	Ml22-2391
Customer No	021567
Title: Semiconductor Processing Methods	of Forming a Contact Opening to a
Conductive Line and Methods of	f Forming Substrate Active Area
Source/Drain Regions	

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

The attached Form PTO-1449 is submitted In compliance with 37 C.F.R. §§ 1.56, 1.97 and 1.98, your attention is directed to the references listed on the attached Form PTO-1449. Pursuant to Federal Register Vol. 69, No. 182, pg. 56542 (September 21, 2004), no copies of any cited U.S. patents or U.S. published applications are included herewith. Copies of all other cited art references, if any, are attached. No admission is made regarding whether the submitted references are prior art.

Citation of this reference is respectfully requested.

Respectfully submitted,

D. Brent Kenady Reg. No. 40,045

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U.S. PATENT DOCUMENTS												
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